



Switcher and DCD Status



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Belle 2 PXD

EVO-Meeting

25.08.2009

Switcher

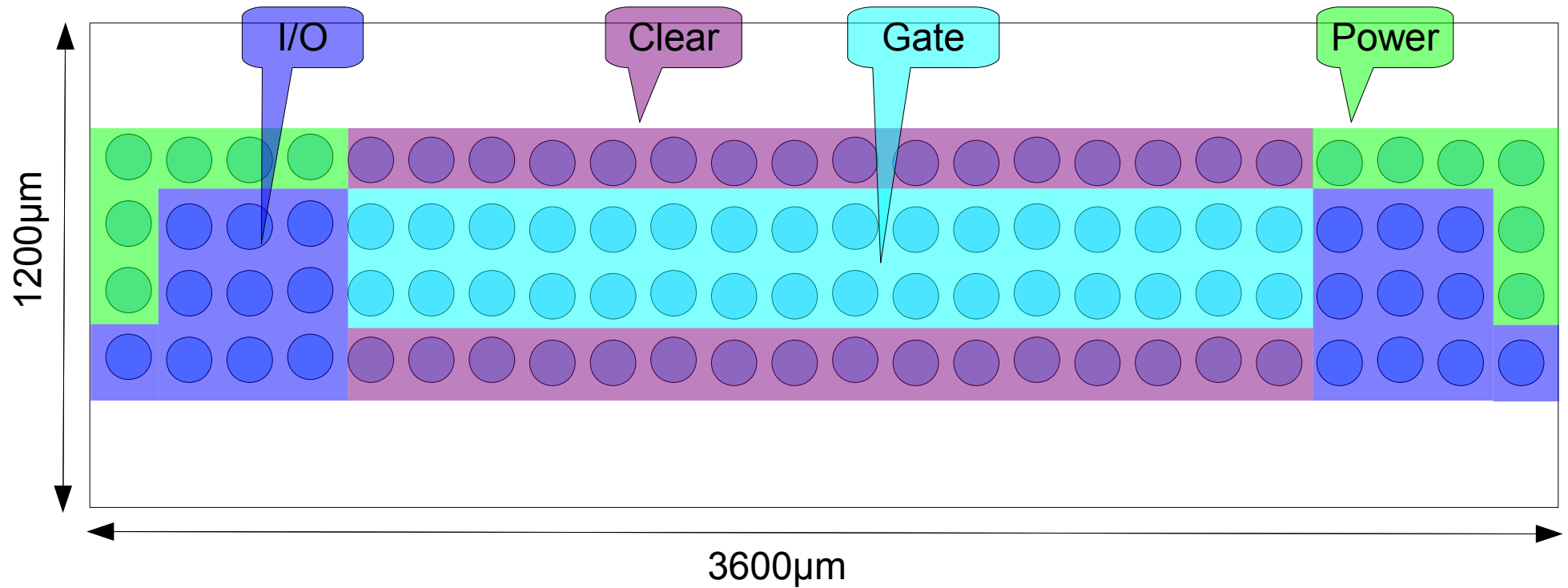
Switcher-B Summary

- AMS 0.35 μ m high voltage technology
 - 1200 μ m x 3600 μ m chip size
 - 150 μ m bump pitch, 70 μ m Al-pads
 - 96 pads (32 Gate, 32 Clear, 14 Power, 16 I/O)
 - solder bumps or under bump metallization not available for miniasic
- 32 channels (DEPFET rows)
 - each channel has two outputs (Gate, Clear)
 - max 20V swing
 - GateHi, GateLo, ClearHi, ClearLo Power Inputs
 - channel selected sequentially with shift register
 - outputs of channel controlled by strobe signals
 - shift registers of neighboring chips can be daisy chained
 - shift clk, serin, serout, strobcs are LVDS signals
 - build-in decoupling of Clear and Gate to DEPFET-source potential
 - capacitive coupling of control and output stage to reduce static power

Switcher-B Summary

- LVDS
 - uses 3.3V digital supply
 - configurable termination resistor and output current
- JTAG interface
 - testing and configuration of chip
 - uses 1.8V supply from DHP
 - configuration bits are triplicated and secured with majority voter
 - SEU can be detected by reading back registers

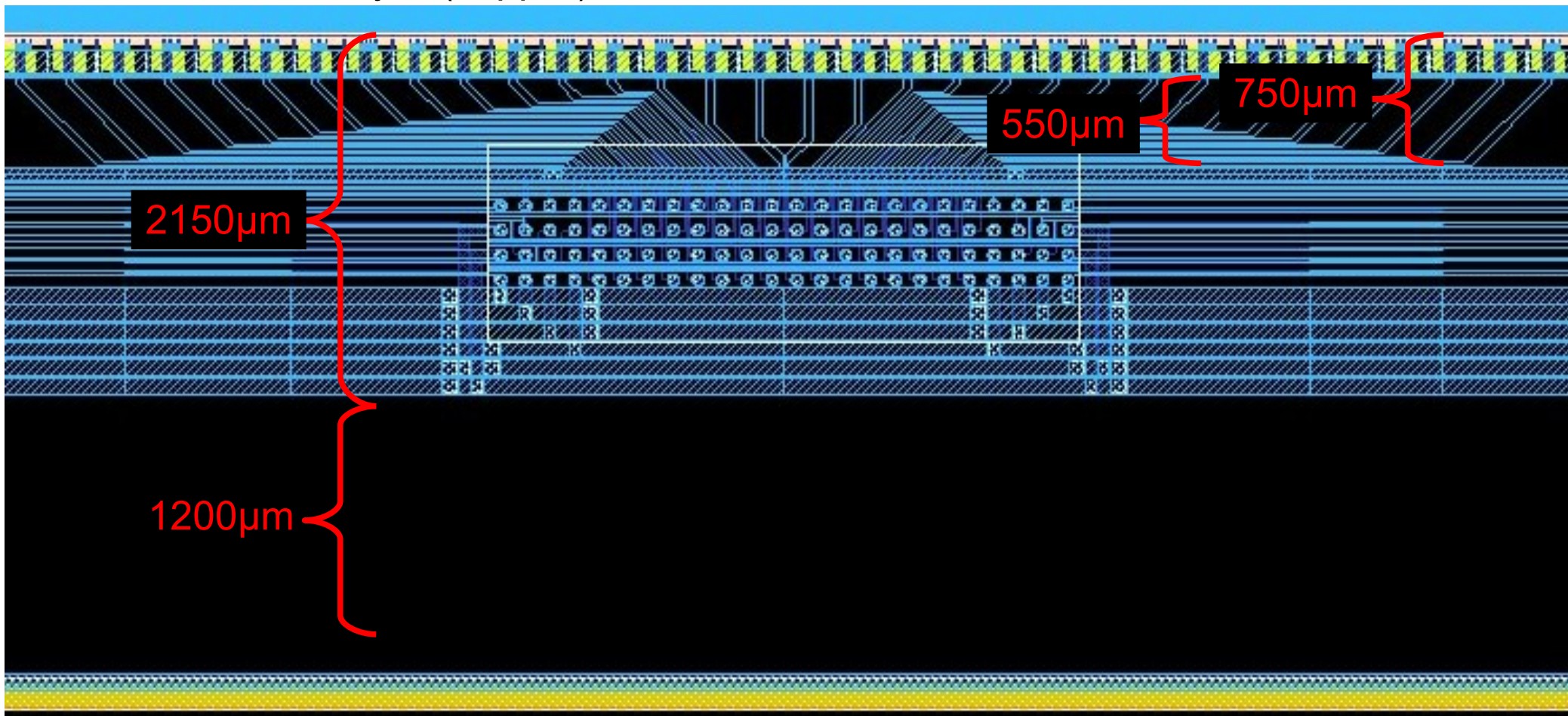
Switcher-B Pad functionality



Switcher Bump Pad Layout

Switcher Balcony PXD6

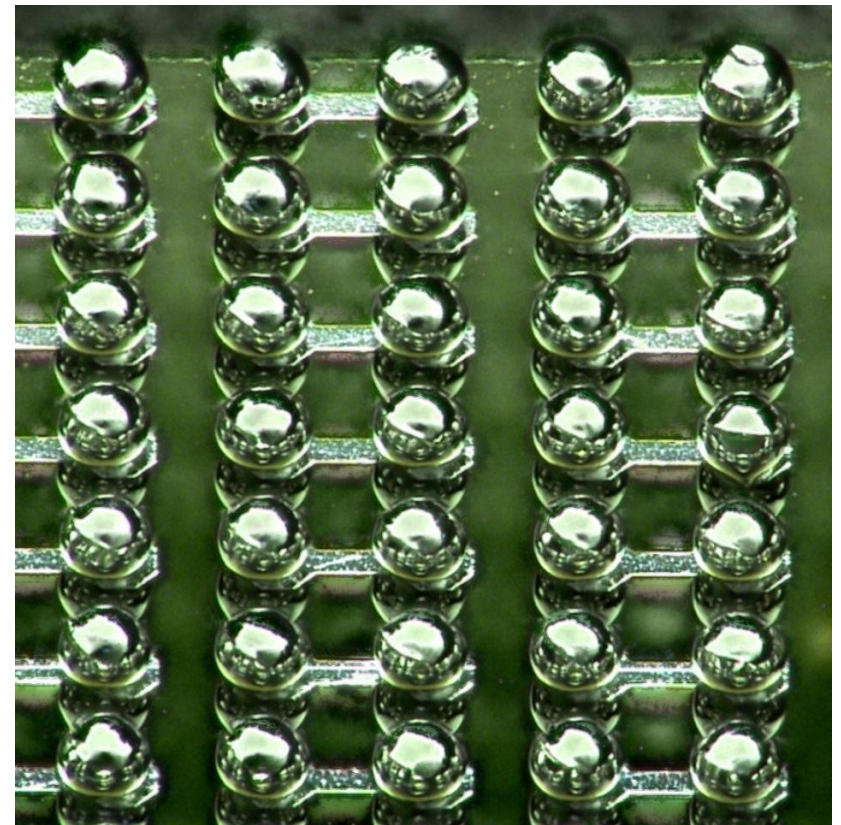
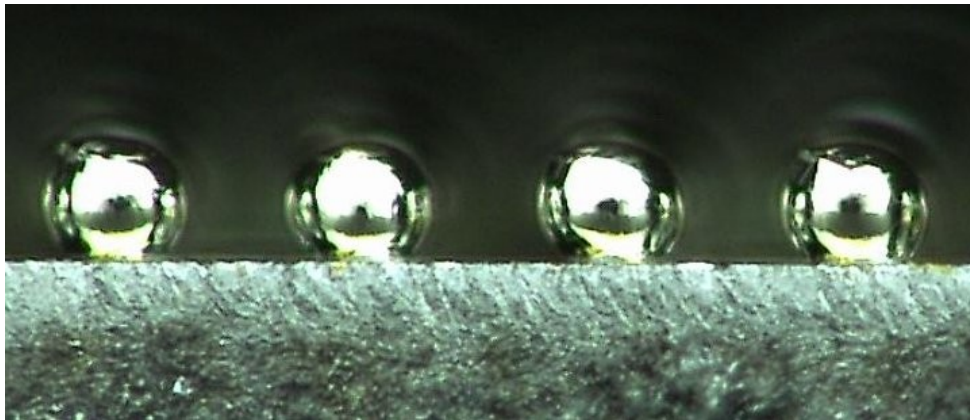
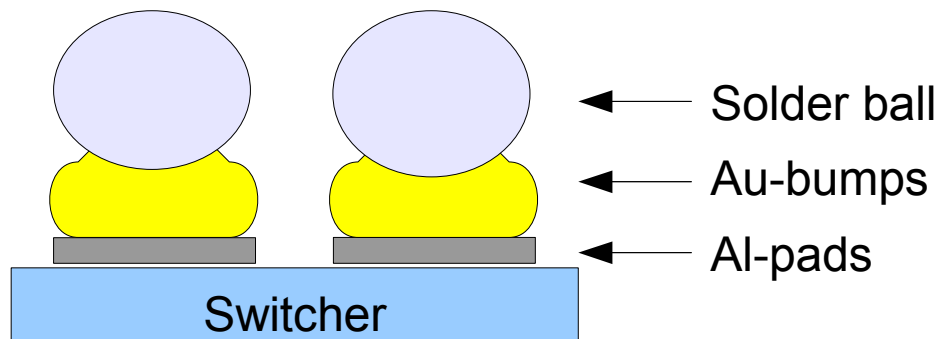
- both metal layer used in parallel to reduce R where possible
- PXD6 design will use free space for power busses
- balcony design fits in 2mm final module by shrinking power bus
 - 3rd metal layer (copper) will be available to reduce R



- rough estimation calculated
 - more detailed simulation and extraction ongoing
- worst case on longest PXD6 module (Z100 type)
- control busses
 - ~5cm length
 - 2 metal layers parallel where possible
 - $t_{RC} = \sim 3.6\text{ns}$
- fanout from switcher to matrix
 - longest line ~6.2mm
 - 2 metal layer, 3rd metal not available due to small trace width
 - adds ~8pF to matrix capacitance
 - $t_{RC} = \sim 830\text{ps}$ (10% $\leftrightarrow$ 90%) for 58pF
- power bus
 - ~5cm length
 - PXD6: 300 μm width, 2 metal layer, 15m Ω /sq: 2,5 Ω
 - final module: 75 μm width, 3 metal layer, 3,75m Ω /sq: 2,5 Ω

Bumping

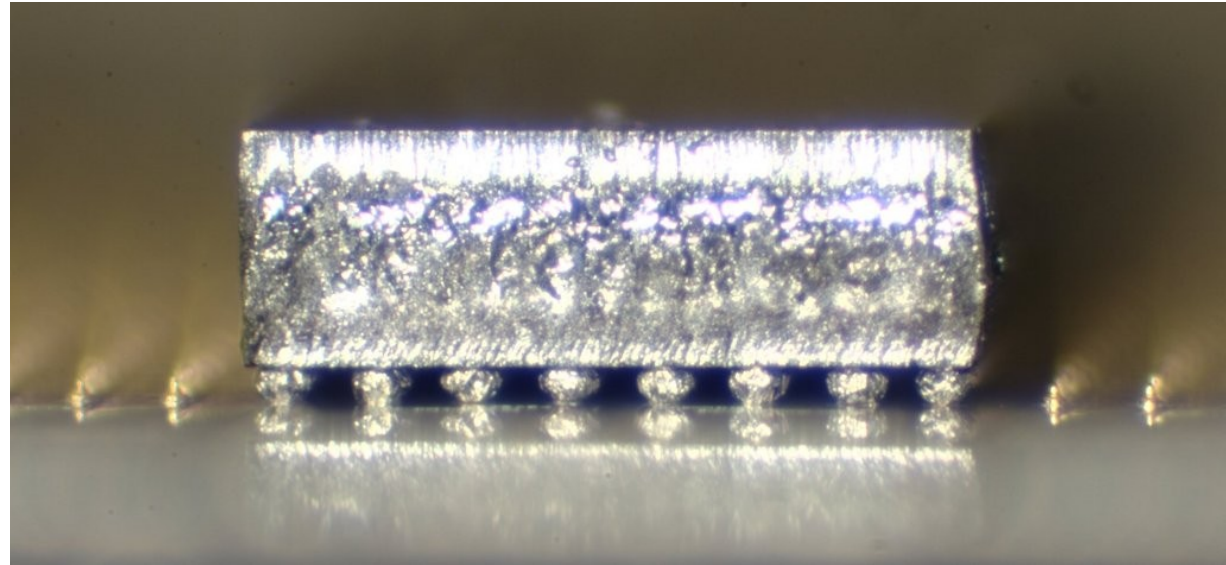
- commercial solder bumping not available for switcher
- use coined gold studs as under bump metallization
- place solder bumps ontop using PacTec technology
 - 55 μ m placed ball diameter



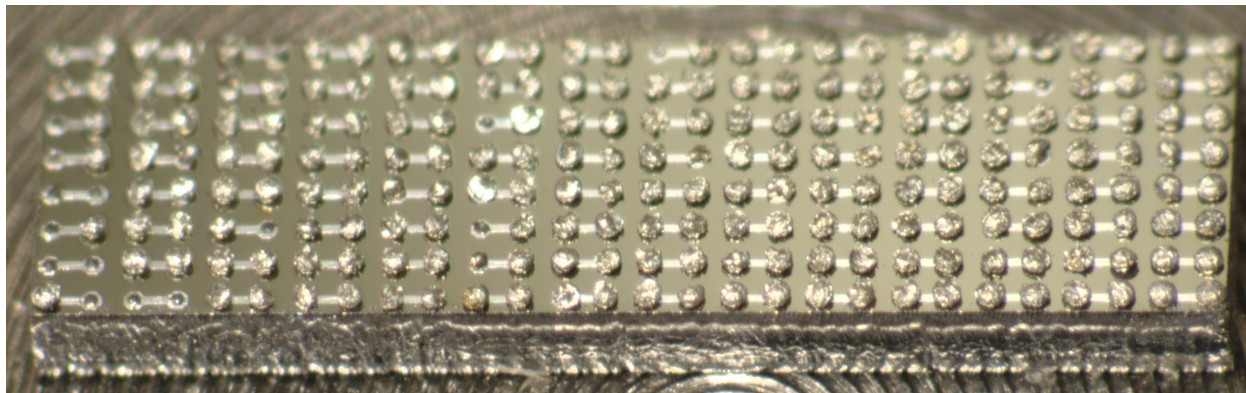
side and top view of dummy chip with PacTec solder ball placed ontop of coined gold bumps

PacTec solder bumping

- send some samples with coined gold bumps to PacTec
- received solder balled samples
- successfully soldered
- successfully desoldered



side view of one soldered chip on a tripple substrate

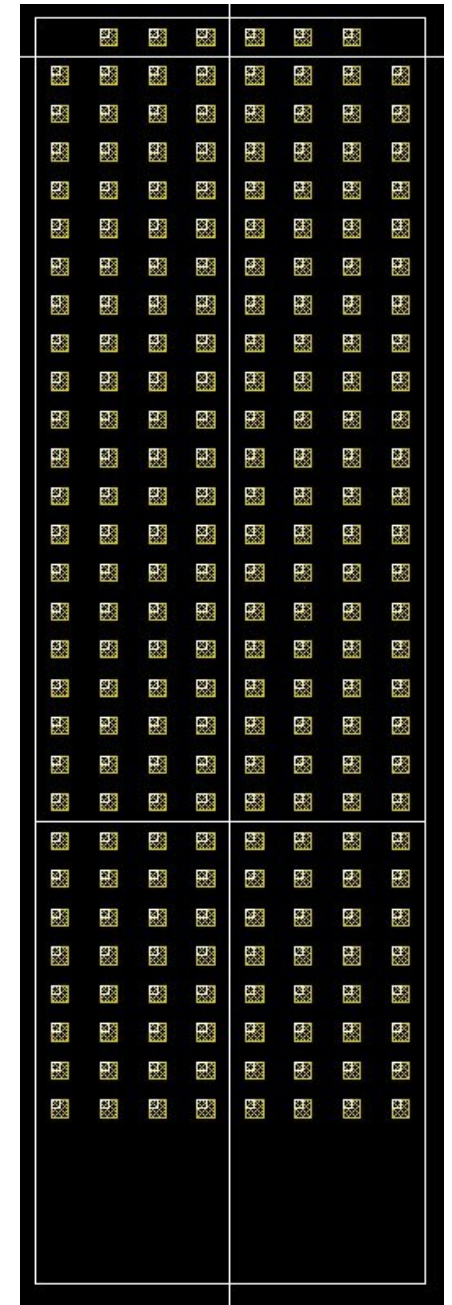


top view of an desoldered chip

DCD

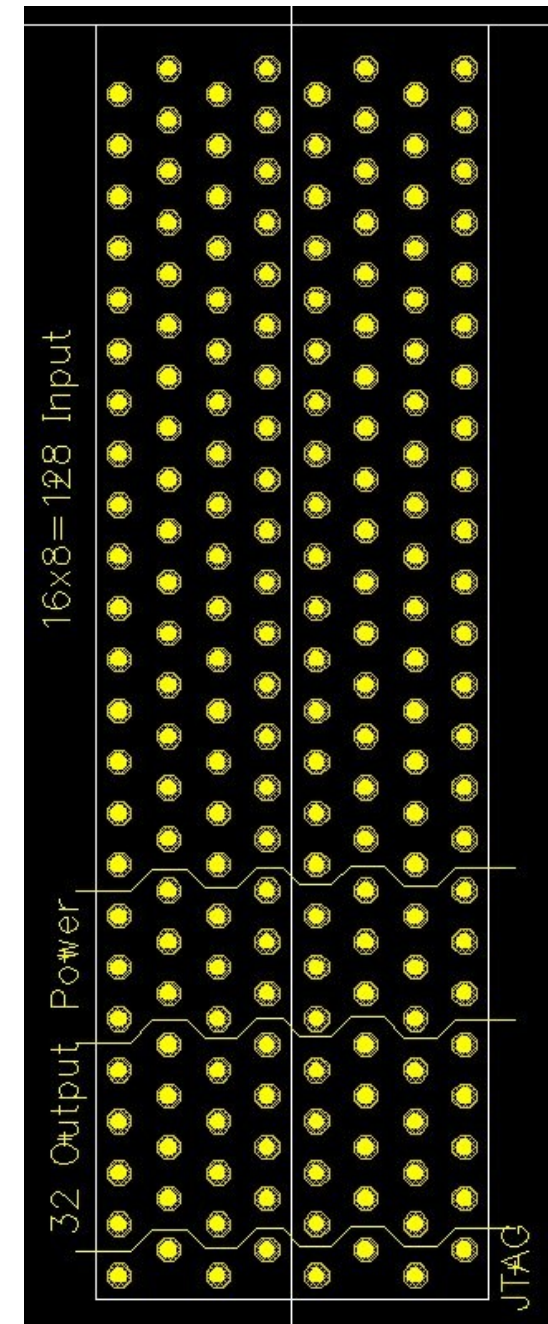
DCD geometry

- received the design rules for commercial solder bumping of DCD
 - 200 μ m bump pitch, 140 μ m gap
 - bumping subcontractor
 - no force when bumping: electronics below pad ok
- current DCD geometry
 - 1x3 size miniasic (1525 μ m x 5000 μ m)
 - UMC 0.18 μ m technology
 - 160 Inputs, 190 μ m pitch in x, 150 μ m in y
 - 5 DCD for PXD6
 - 7 DCD for final design (1000 drains)
- not suitable for bumping by UMC



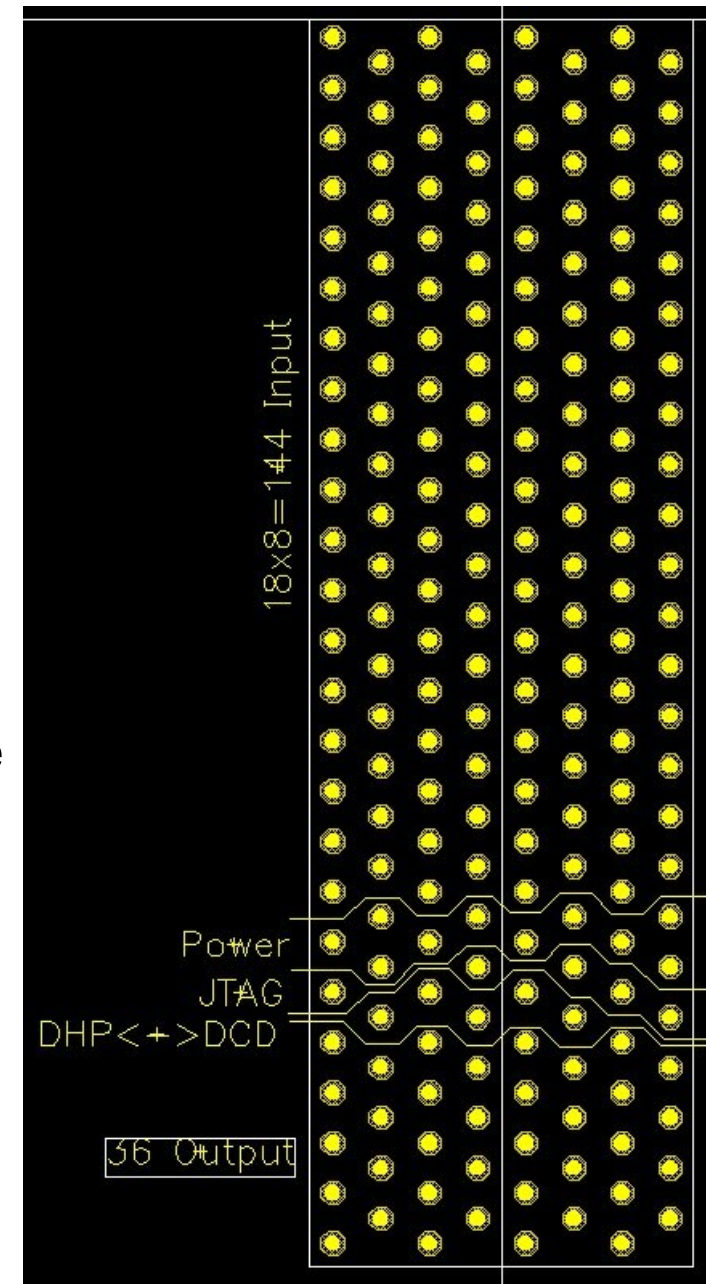
DCD solderball geometry

- 1x3 size with UMC solderbumps
 - DRC clean bump layout
 - 128 Inputs only
 - 6 DCD for PXD6
 - 8 DCD for final design (1000 drains)
 - too few pads for power and control signals
 - space on module wasted by gap between chips



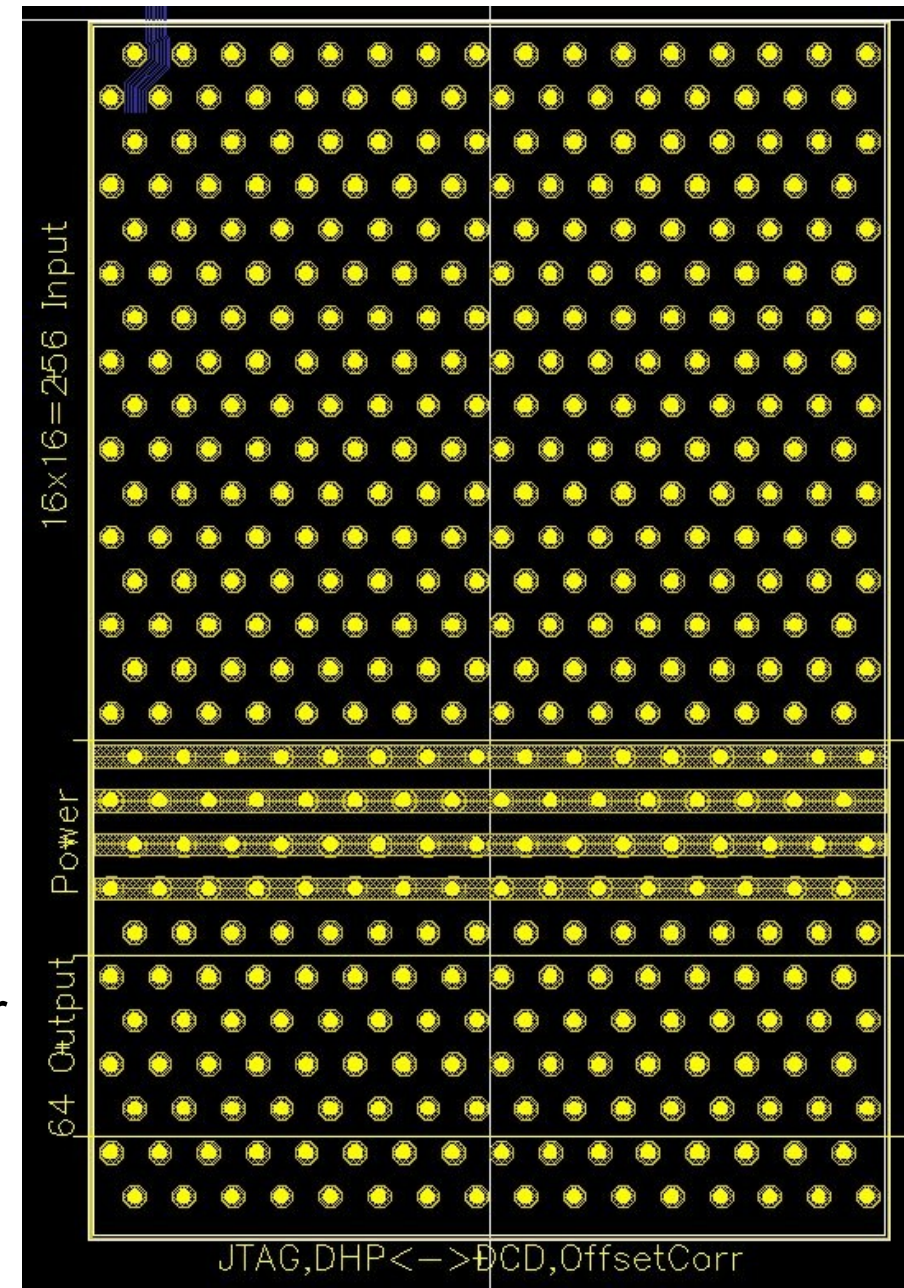
DCD solderball geometry

- 1x3 size with UMC solderbumps
 - 144 Inputs
 - 6 DCD for PXD6
 - 7 DCD for final design (1000 drains)
 - 1 DCD less
 - DRC violated by $1\mu\text{m}$ per bump
 - problem with solder reflow?
 - should not be problem for under bump metallization chemistry
 - question: get chips with UBM only and place solderballs with PacTec machine?
 - likely not possible, because MPW runs are not flexible
 - even less pads for power and control signals than previous 128 input design

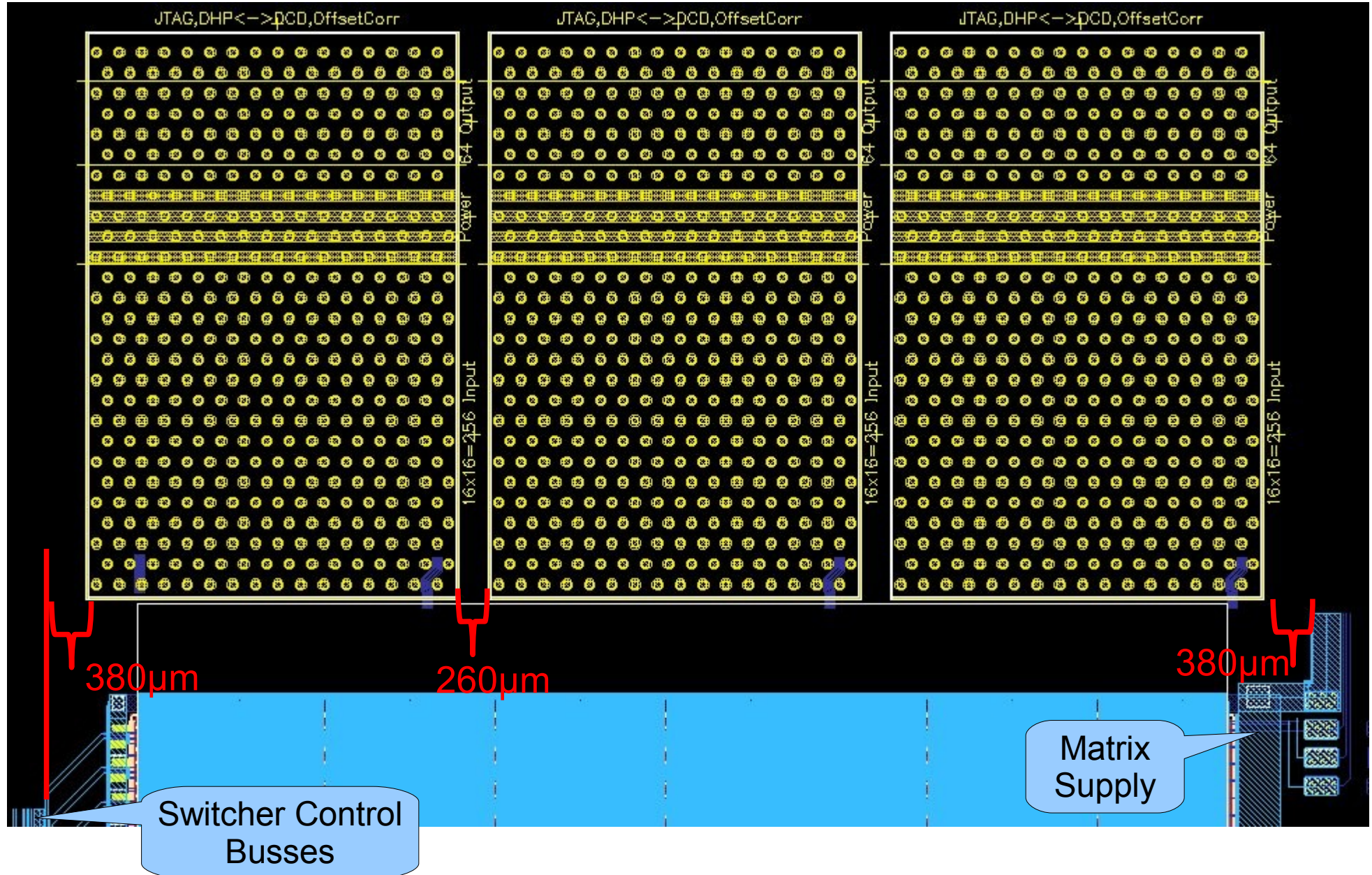


proposed DCD geometry

- new geometry proposal
 - 2x3 miniasic: 3280 μ m x 5000 μ m chip size
 - bump pitch: 200 μ m in x, 180 μ m in y (staggered), DRC clean design
 - 7th metal layer available for connecting bump pads to input cells
 - 6th metal layer free: routing and wide power busses $\rightarrow$ low voltage drop
 - 256 Inputs
 - 3 DCD for PXD6
 - 4 DCD for final design (1000 drains)
 - input cell size: 200 μ m x 130 μ m
 - gain space for onchip decoupling or offset correction memory
 - lower voltage drop across cell array
 - plenty of pads for power and control



proposed DCD at PXD6 Array



- 4 DCDs
 - 3280 μ m design width
 - cutting edge: 55-65 μ m
 - gap between chips >200 μ m
 - space needed: 13720 μ m
- active area 12500 μ m width
- 1220 μ m wider than active area: 610 μ m left and right
 - left side ok: 750 μ m space between active and switcher control busses
 - right side:
 - ~350 μ m occupied for matrix supply (Source, Bias), could be smaller with copper layer
 - 470 μ m needed for the right DCD if chips are left-aligned
- Increase active area by 6 columns to use all DCD channels?
 - 4 DCDs x 256 Inputs = 1024 possible drains

Thank you!